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Photon-in Photon-out Spectroscopy of Functional Materials using Synchrotron Radiation

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Using a phosphor to “see” X-rays is as old as the discovery of X-rays and is practiced everyday worldwide. The advent of maturing third generation synchrotron light source technology has made it possible to conduct investigations of X-ray excited optical luminescence (XEOL) from solid in both energy and time domain in much greater details than ever before.

In parallel with this development are the advancement of optics and detectors, making it possible to provide energy resolution to an unprecedented level. This together with the brightness of the SR source has made the previously difficult experiments such as high resolution X-ray emission/ resonant inelastic X-ray scattering nearly routine. In this talk, I'll describe some of these developments and their implications.

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